

RoHS Compliant Product
 A suffix of "-C" specifies halogen and lead-free

DESCRIPTION

The SMG2325 is the N-Channel logic enhancement mode power field effect transistors are produced using high Cell density, DMOS trench technology. This high density process is especially tailored to minimize on-state Resistance

FEATURES

- Simple Drive Requirement
- Small Package Outline

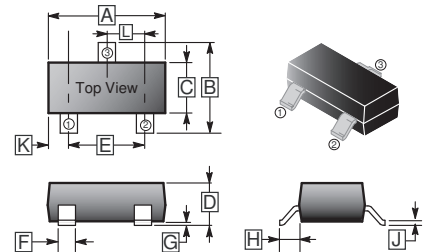
MARKING

2325

PACKAGE INFORMATION

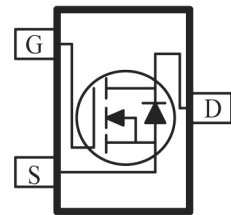
Package	MPQ	Leader Size
SC-59	3K	7 inch

SC-59



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	2.70	3.10	G	0.10	REF.
B	2.25	3.00	H	0.40	REF.
C	1.30	1.70	J	0.10	0.20
D	1.00	1.40	K	0.45	0.55
E	1.70	2.30	L	0.85	1.15
F	0.35	0.50			

TOP VIEW



ABSOLUTE MAXIMUM RATINGS ($T_A=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	V_{DS}	250	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current ¹ , $V_{GS}@10\text{V}$	I_D	$T_A=25^\circ\text{C}$	0.45
		$T_A=70^\circ\text{C}$	0.35
Pulsed Drain Current ²	I_{DM}	1.4	A
Power Dissipation ³	P_D	0.8	W
Operating Junction and Storage Temperature Range	T_j, T_{stg}	-55~150	$^\circ\text{C}$
Thermal Resistance Rating			
Maximum Junction to Ambient ¹	$R_{\theta JA}$	156	$^\circ\text{C} / \text{W}$

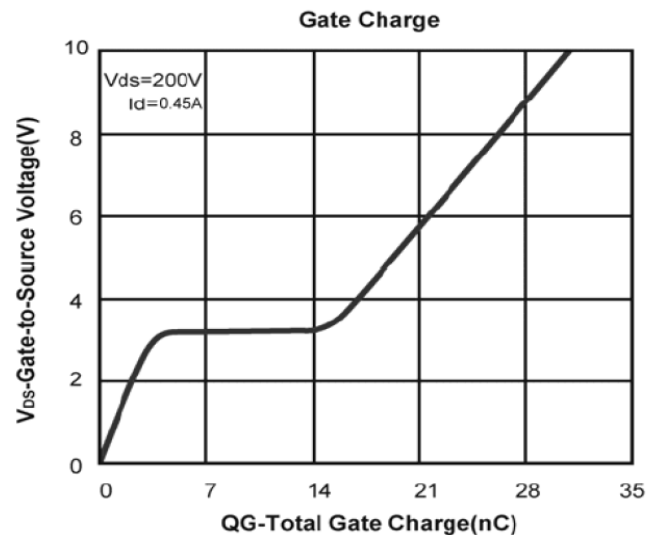
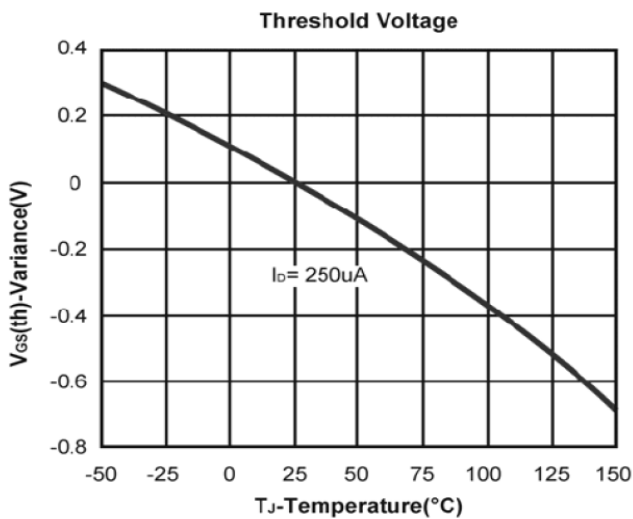
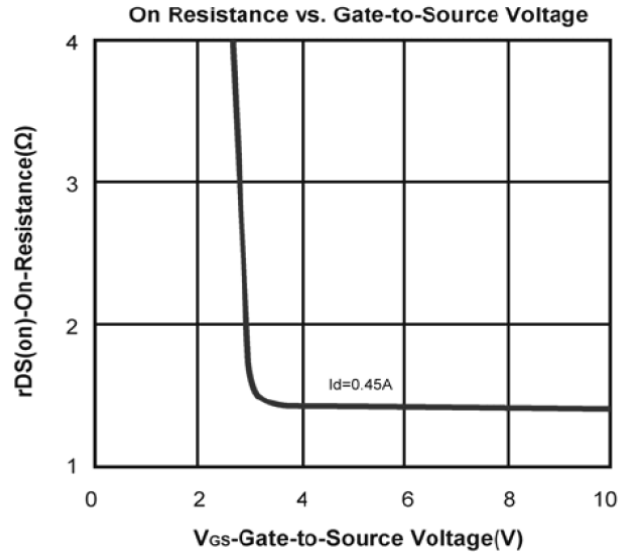
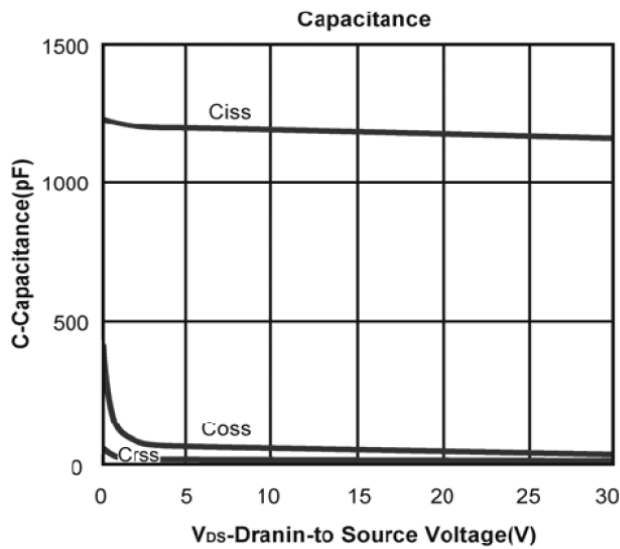
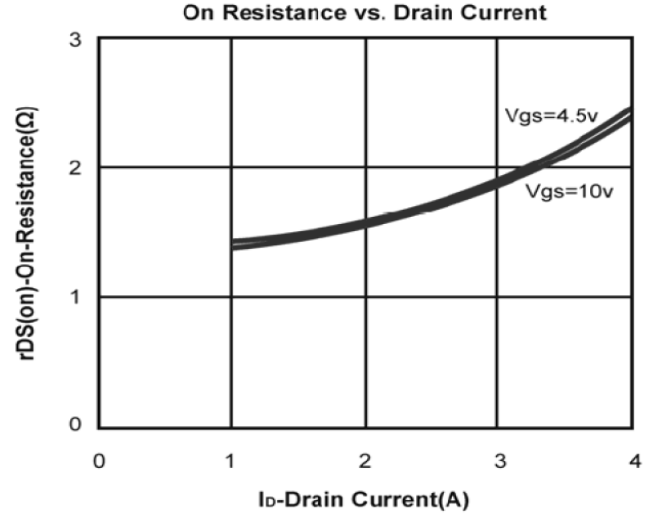
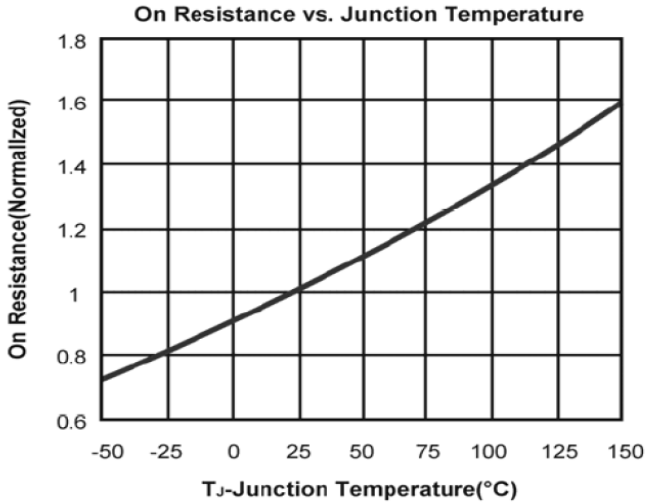
ELECTRICAL CHARACTERISTICS ($T_A=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Teat Conditions
Static						
Drain-Source Breakdown Voltage	BV_{DSS}	250	-	-	V	$V_{GS}=0, I_D=250\mu\text{A}$
Gate-Threshold Voltage	$V_{GS(th)}$	1.5	-	3.5	V	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$
Gate-Body Leakage Current	I_{GSS}	-	-	± 100	nA	$V_{GS}=\pm 20\text{V}$
Drain-Source Leakage Current	I_{DSS}	-	-	1	μA	$V_{DS}=250\text{V}, V_{GS}=0$
Drain-Source On-Resistance ¹	$R_{DS(ON)}$	-	-	1.7	Ω	$V_{GS}=10\text{V}, I_D=0.45\text{A}$
		-	-	1.9		$V_{GS}=4.5\text{V}, I_D=0.35\text{A}$
Diode Forward Voltage ¹	V_{SD}	-	-	1.2	V	$I_S=0.45\text{A}, V_{GS}=0$
Dynamic						
Total Gate Charge	Q_g	-	30	-	nC	$V_{DS}=200\text{V}, V_{GS}=10\text{V}, I_D=0.45\text{A}$
Total Gate Charge	Q_g	-	17	-		$V_{DS}=200\text{V},$ $V_{GS}=4.5\text{V},$ $I_D=0.45\text{A}$
Gate-Source Charge	Q_{gs}	-	3	-		
Gate-Drain ("Miller") Charge	Q_{gd}	-	12	-		
Turn-on Delay Time ¹	$T_{d(on)}$	-	19	-	nS	$V_{DD}=125\text{V},$ $V_{GS}=10\text{V},$ $R_G=6\Omega,$ $R_L=125\Omega,$ $I_D=0.45\text{A}$
Rise Time	T_r	-	4	-		
Turn-off Delay Time	$T_{d(off)}$	-	48	-		
Fall Time	T_f	-	13	-		
Input Capacitance	C_{iss}	-	1170	-	pF	$V_{GS}=0,$ $V_{DS}=15\text{V},$ $f=1.0\text{MHz}$
Output Capacitance	C_{oss}	-	36	-		
Reverse Transfer Capacitance	C_{rss}	-	10	-		

Notes:

1. Surface mounted on a 1 inch² FR-4 board with 2OZ copper. ;270°C /W when mounted on min. copper pad.
2. The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
3. The power dissipation is limited by 150°C juncti on temperature
4. The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

CHARACTERISTIC CURVES



CHARACTERISTIC CURVES

